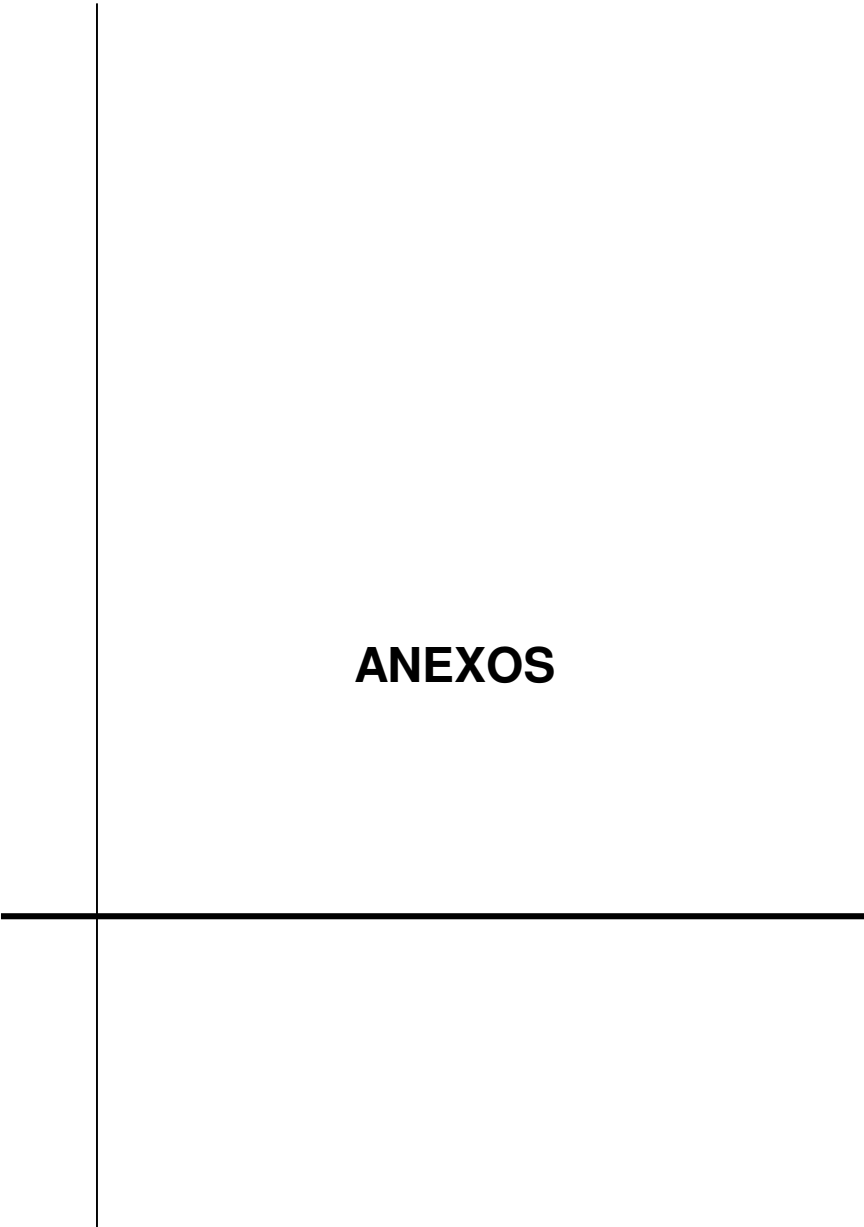




ANEXOS

7. ANEXOS

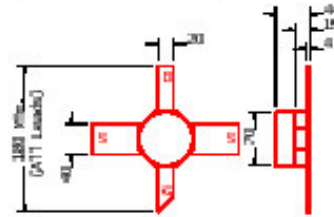
7.1. HOJA DE CATÁLOGO DEL TRANSISTOR EPB018A5-70



EPB018A5/A7/A9-70

DATA SHEET Super Low Noise High Gain Heterojunction FET

- NON-HERMETIC LOW COST CERAMIC 70 mil PACKAGE
- TYPICAL 0.50~0.90dB NOISE FIGURE AND 11.5~13.0dB ASSOCIATED GAIN AT 12GHz
- 0.3 X 180 MICRON RECESSED " MUSHROOM" GATE
- Si_3N_4 PASSIVATION
- ADVANCED EPITAXIAL HETEROJUNCTION PROFILE PROVIDES SUPER LOW NOISE, HIGH GAIN AND HIGH RELIABILITY



All Dimensions In mils.

ELECTRICAL CHARACTERISTICS ($T_1 = 25^\circ\text{C}$)

SYMBOLS	PARAMETERS/TEST CONDITIONS	MIN	TYP	MAX	UNIT
NF	Noise Figure, $f=12\text{GHz}$ $V_{ds}=2\text{V}$, $I_{ds}=15\text{mA}$	EPB018A5-70	0.50	0.60	dB
		EPB018A7-70	0.65	0.80	
		EPB018A9-70	0.95	1.20	
Ga	Associated Gain, $f=12\text{GHz}$ $V_{ds}=2\text{V}$, $I_{ds}=15\text{mA}$	EPB018A5-70	11.5	13.0	dB
		EPB018A7-70	11.0	12.5	
		EPB018A9-70	10.5	11.5	
P_{1dB}	Output Power at 1dB Compression $V_{ds}=3\text{V}$, $I_{ds}=25\text{mA}$	$f=12\text{GHz}$	15.0		dBm
		$f=18\text{GHz}$	15.0		
G_{1dB}	Gain at 1dB Compression $V_{ds}=3\text{V}$, $I_{ds}=25\text{mA}$	$f=12\text{GHz}$	14.0		dB
		$f=18\text{GHz}$	11.5		
I_{dss}	Saturated Drain Current $V_{ds}=2\text{V}$, $V_{gs}=0\text{V}$	15	45	80	mA
G_m	Transconductance $V_{ds}=2\text{V}$, $V_{gs}=0\text{V}$	50	90		mS
V_p	Pinch-off Voltage $V_{ds}=2\text{V}$, $I_{ds}=1.0\text{mA}$		-0.8	-2.5	V
BV_{gd}	Drain Breakdown Voltage $I_{gd}=10\mu\text{A}$	-3	-6		V
BV_{gs}	Source Breakdown Voltage $I_{gs}=10\mu\text{A}$	-3	-6		V
R_{th}	Thermal Resistance		480*		$^\circ\text{C/W}$

* Overall R_{th} depends on case mounting.

MAXIMUM RATINGS AT 25°C

SYMBOLS	PARAMETERS	ABSOLUTE ¹	CONTINUOUS ²
V_{ds}	Drain-Source Voltage	5V	4V
V_{gs}	Gate-Source Voltage	-3V	-2V
I_{ds}	Drain Current	I_{dss}	60mA
I_{gsf}	Forward Gate Current	2mA	0.3mA
P_{in}	Input Power	12dBm	@ 1dB Compression
T_{ch}	Channel Temperature	175 $^\circ\text{C}$	150 $^\circ\text{C}$
T_{stg}	Storage Temperature	-65/175 $^\circ\text{C}$	-65/150 $^\circ\text{C}$
P_t	Total Power Dissipation	285mW	240mW

Note: 1. Exceeding any of the above ratings may result in permanent damage.

2. Exceeding any of the above ratings may reduce MTTF below design goals.

Excelics Semiconductor, Inc., 2908 Scott Blvd., Santa Clara, CA 95054

Phone: (408) 970-8664 Fax: (408) 970-8998 Web Site: www.excelics.com

EPB018A5/A7/A9-70

DATA SHEET

Super Low Noise High Gain Heterojunction FET

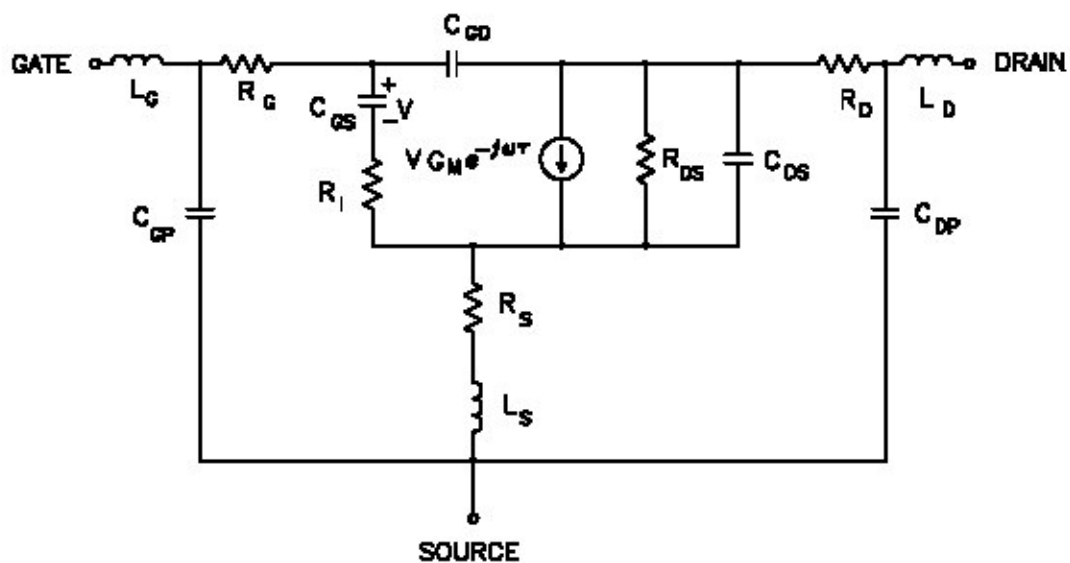
EPB018A5-70										EPB018A7-70									
S-PARAMETERS										S-PARAMETERS									
2V, 15mA										2V, 15mA									
FREQ	-- S11 --		-- S21 --		-- S12 --		-- S22 --			FREQ	-- S11 --		-- S21 --		-- S12 --		-- S22 --		
(GHz)	MAG	ANG	MAG	ANG	MAG	ANG	MAG	ANG		(GHz)	MAG	ANG	MAG	ANG	MAG	ANG	MAG	ANG	
1.0	0.983	-18.6	6.245	162.2	0.019	78.9	0.530	-13.5		1.0	0.985	-18.9	5.754	162.0	0.021	77.1	0.677	-13.7	
2.0	0.944	-37.5	5.964	144.3	0.036	65.2	0.507	-28.8		2.0	0.949	-38.2	5.495	143.9	0.040	63.1	0.650	-28.9	
3.0	0.896	-55.5	5.582	127.7	0.050	53.6	0.485	-42.6		3.0	0.903	-56.2	5.137	127.2	0.055	50.5	0.622	-42.7	
4.0	0.849	-72.6	5.327	112.4	0.063	43.6	0.464	-54.2		4.0	0.860	-73.6	4.914	111.8	0.067	39.1	0.595	-54.1	
5.0	0.797	-89.2	5.111	97.6	0.074	33.1	0.421	-65.4		5.0	0.812	-90.4	4.726	96.9	0.079	28.5	0.549	-65.4	
6.0	0.747	-103.7	4.799	83.4	0.081	23.4	0.370	-78.6		6.0	0.765	-104.9	4.461	82.4	0.086	17.8	0.495	-78.6	
7.0	0.691	-118.6	4.503	69.9	0.085	13.9	0.344	-90.7		7.0	0.713	-119.9	4.189	68.6	0.092	7.3	0.464	-90.5	
8.0	0.642	-132.8	4.277	57.0	0.088	4.7	0.303	-100.7		8.0	0.664	-134.3	3.982	55.4	0.093	-3.6	0.411	-100.6	
9.0	0.600	-155.6	4.189	42.7	0.093	-5.1	0.271	-111.2		9.0	0.621	-157.1	3.908	40.9	0.096	-12.9	0.374	-108.6	
10.0	0.567	-178.3	4.012	27.8	0.096	-16.3	0.228	-126.9		10.0	0.591	-179.4	3.759	25.7	0.098	-24.5	0.328	-121.7	
11.0	0.534	-170.3	3.846	15.5	0.094	-26.5	0.193	-145.5		11.0	0.564	-169.0	3.644	12.8	0.099	-33.4	0.295	-140.0	
12.0	0.515	-155.6	3.758	2.9	0.093	-33.1	0.177	-161.2		12.0	0.541	-153.2	3.551	-0.8	0.098	-43.3	0.266	-157.6	
13.0	0.555	-128.7	3.569	-12.5	0.091	-44.2	0.137	-176.3		13.0	0.574	-126.2	3.360	-16.6	0.096	-54.9	0.210	-174.2	
14.0	0.596	-106.0	3.317	-27.1	0.088	-55.6	0.114	-151.4		14.0	0.609	-103.6	3.093	-31.7	0.090	-66.7	0.173	-167.6	
15.0	0.592	-91.3	3.214	-41.3	0.087	-66.9	0.141	-123.9		15.0	0.598	-88.8	2.985	-46.4	0.090	-78.4	0.187	-139.8	
16.0	0.597	-74.3	3.086	-56.8	0.083	-81.1	0.158	-94.5		16.0	0.597	-71.4	2.857	-62.2	0.085	-92.9	0.194	-109.8	
17.0	0.619	-59.2	2.756	-69.5	0.071	-90.3	0.134	-68.1		17.0	0.612	-55.7	2.548	-75.5	0.072	-102.8	0.155	-89.8	
18.0	0.670	-49.9	2.668	-79.4	0.071	-97.3	0.136	-64.0		18.0	0.661	-46.6	2.472	-85.8	0.076	-105.2	0.183	-89.7	
19.0	0.668	-33.0	2.623	-95.4	0.069	-115.9	0.169	-51.0		19.0	0.657	-29.0	2.381	-102.1	0.076	-126.2	0.221	-68.8	
20.0	0.708	-17.3	2.551	-111.1	0.064	-131.4	0.172	-37.8		20.0	0.697	-13.2	2.286	-118.1	0.071	-141.6	0.240	-56.1	
21.0	0.757	-8.2	2.447	-125.1	0.061	-144.1	0.159	-18.7		21.0	0.740	-4.4	2.173	-131.8	0.068	-155.3	0.221	-40.9	
22.0	0.743	-2.5	2.325	-139.4	0.063	-159.2	0.135	-14.7		22.0	0.728	-5.8	2.067	-145.9	0.070	-167.9	0.210	-36.8	
23.0	0.726	-21.1	2.224	-158.5	0.065	-179.4	0.115	-1.3		23.0	0.717	-24.4	1.958	-164.5	0.071	-172.5	0.188	-21.8	
24.0	0.747	-39.6	2.063	-178.1	0.067	-158.8	0.102	-39.6		24.0	0.743	-41.8	1.807	-176.3	0.071	-151.8	0.154	-5.5	
25.0	0.709	-52.6	2.024	-167.9	0.072	-144.7	0.136	-56.6		25.0	0.710	-53.5	1.757	-161.7	0.075	-138.3	0.174	-28.1	
26.0	0.683	-70.6	2.006	-150.2	0.083	-132.8	0.117	-71.3		26.0	0.689	-69.1	1.759	-145.4	0.084	-124.1	0.152	-47.5	

EPB018A7-70 Noise Parameters Vds=2V, Ids=15mA				
Freq.	Gamma Opt		Nfmin	Rn/50
(GHz)	(MAG)	(ANG)	(dB)	
2	0.76	25	0.37	0.26
4	0.65	56	0.43	0.22
6	0.51	84	0.48	0.16
8	0.41	118	0.55	0.11
10	0.26	159	0.61	0.08
12	0.26	-144	0.68	0.08
14	0.32	-82	0.89	0.18
16	0.40	-46	1.10	0.29
18	0.40	-26	1.30	0.45
20	0.51	8	1.45	0.55
22	0.41	27	1.69	0.61
24	0.48	75	1.83	0.59
26	0.52	108	2.05	0.40



Small Signal Equivalent Circuit Model

The small signal model shown below can be useful for extrapolating and interpolating the S-parameters as well as for use in circuit simulators that cannot handle S-parameters directly. The element values are derived by fitting the calculated S-parameters of the model to measured data. The bias points and bonding configuration are as described in the individual device data sheets.



SMALL SIGNAL MODEL



Small Signal Model Element Values High Efficiency Heterojunction Power FETs

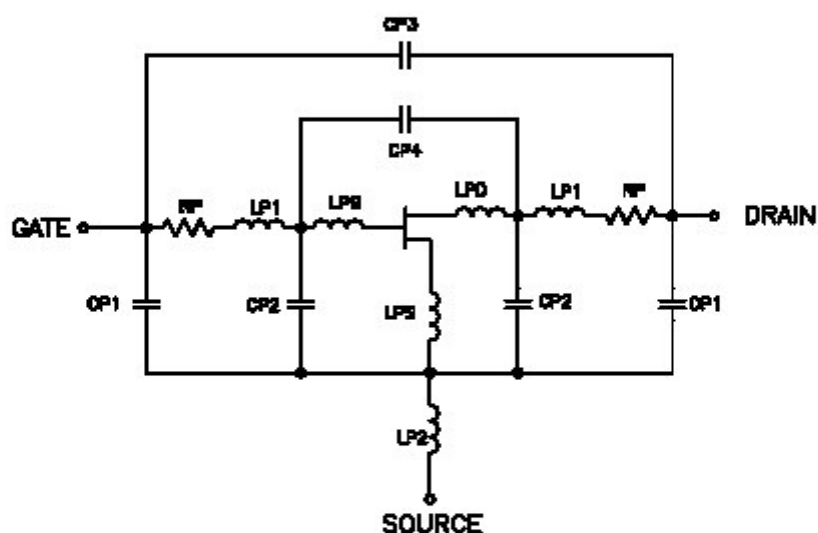
Parameter	L_G nH	R_G Ω	C_{GS} pF	R_I Ω	R_S Ω	L_S nH	C_{GD} pF	R_{DS} Ω	C_{DS} pF	R_D Ω	L_D nH	G_M mS	τ pS	C_{KG} pF	C_{PD} pF
Device:															
EPA018A	0.18	0.50	0.30	0.29	0.13	0.057	0.021	680	0.011	1.0	0.22	55	2.5	0.06	0.06
EPA025A	0.10	1.8	0.33	1.9	0.83	0.071	0.014	280	0.044	1.38	0.18	84	2.0	0.17	0.17
EPA030C	0.20	0.55	0.59	1.6	0.69	0.041	0.024	300	0.025	0.41	0.30	110	2.0	0.084	0.084
EPA040A	0.20	0.74	0.67	1.2	0.52	0.037	0.031	210	0.043	0.55	0.30	140	2.0	0.084	0.084
EPA060A	0.10	0.28	1.2	0.80	0.35	0.028	0.046	120	0.044	0.21	0.15	250	2.0	0.17	0.17
EPA060B	0.20	0.71	1.0	0.80	0.35	0.035	0.044	160	0.064	0.53	0.33	190	2.0	0.084	0.084
EPA080A	0.10	0.37	1.4	0.60	0.26	0.028	0.058	96	0.097	0.28	0.18	260	2.0	0.17	0.17
EPA090A	0.067	0.18	1.6	0.53	0.23	0.022	0.060	73	0.078	0.14	0.089	350	2.0	0.25	0.25
EPA120A	0.067	0.25	1.9	0.40	0.17	0.020	0.085	60	0.16	0.18	0.094	400	2.0	0.25	0.25
EPA120B	0.10	0.35	2.1	0.40	0.17	0.023	0.088	75	0.15	0.26	0.13	380	2.0	0.17	0.17
EPA120E	0.050	0.14	2.1	0.40	0.17	0.018	0.078	52	0.12	0.10	0.045	460	2.0	0.34	0.34
EPA160A	0.050	0.18	2.4	0.30	0.13	0.016	0.11	37	0.26	0.14	0.084	570	2.0	0.34	0.34
EPA160B	0.10	0.47	3.8	0.30	0.13	0.022	0.15	83	0.21	0.35	0.09	810	2.0	0.17	0.17
EPA240B	0.050	0.18	3.3	0.20	0.087	0.050	0.17	27	0.47	0.13	0.074	740	2.0	0.34	0.34
EPA240D	0.28	1.2	4.3	0.20	0.27	0.12	0.14	95	0.30	0.067	0.49	350	4.0	0.25	0.25
EPA480B	0.050	0.35	6.7	0.10	0.043	0.020	0.34	14	0.62	0.26	0.93	1300	2.0	0.37	0.37
EPA480C	0.14	0.61	8.1	0.10	0.13	0.080	0.28	47	0.60	1.1	0.25	670	4.0	0.50	0.50
EPA720A	0.090	0.40	12	0.067	0.090	0.060	0.42	32	0.90	0.70	0.16	1000	4.0	0.76	0.76
EPA960B	0.070	0.31	16	0.050	0.070	0.048	0.56	24	1.2	0.53	0.12	1400	4.0	1.0	1.0
EPA1200A	0.056	0.24	20	0.040	0.050	0.040	0.72	19	1.5	0.42	0.10	1700	4.0	1.3	1.3
High Gain Heterojunction Low Noise FET															
EPB018A	0.22	1.9	0.15	1.6	0.61	0.018	0.040	270	0.015	1.6	0.19	77	2.0	0.08	0.041
EPB025A	0.10	1.8	0.14	1.9	0.83	0.061	0.060	150	0.060	1.4	0.12	78	2.0	0.17	0.17



EXCELICS SEMICONDUCTOR, INC.

Packaged FET Equivalent Circuit Model

Shown below is an approximate model for use with packaged FETs. The FET shown in the schematic can be replaced with the small signal or large signal model for the chip, including bond wire inductances. The element values shown below for the various packages provide a first order approximation, as the exact values will vary depending on the device type.



PACKAGED FET MODEL

Parameter	Units	SOT-89	70 mil	100 mil flange	180 mil flange	CP083
CP1	pF	0.28	0.038	0.05	0.78	0.52
CP2	pF	0.39	0.13	0.2	0.57	0
LP1	nH	1.2	0.25	0.5	0.61	0.56
RP	ohm	0	0.7	0.8	0	0
CP3	pF	0	0.006	0	0	0
CP4	pF	0.3	0	0	0	0
LPG	nH	0	0.3	0.14	0.34	0.06
LPD	nH	0	0.2	0.1	0.2	0.2
LPS	nH	0.009	0.028	0	0.017	0.018
LP2	nH	0	0.065	0.03	0	0

Excelics EPB018A**Curtice-Cubic GaAsFET Model CURTICE3**

(Curtice-Ettenberg model)

Parameter	Description	Unit	Value
BETA	Coefficient for pinch-off change with respect to V_{ds}	1/V	0.0511
GAMMA	Hyperbolic tangent function parameter	1/V	1.47
VOU0	Output voltage (V_{ds}) at which A0, A1, A2, A3 were evaluated	V	2.51
VT0	Value of V1 below which $I_{ds}=I_{ds}(V1=VT0, V_{ds})$	V	-0.9
A0	Cubic polynomial I_{ds} equation coefficient 1	A	0.0524
A1	Cubic polynomial I_{ds} equation coefficient 2	A/V	0.0839
A2	Cubic polynomial I_{ds} equation coefficient 3	A/V ²	0.0257
A3	Cubic polynomial I_{ds} equation coefficient 4	A/V ³	-0.00493
TAU	Transit time under gate	S	2.00E-12
R1	Approximate breakdown resistance	ohm	0
R2	Resistance relating breakdown voltage to channel current	ohm	0
VB0	Gate-drain junction reverse bias breakdown voltage (gate-source junction reverse bias breakdown voltage with $V_{ds}<0$)	V	8
VBI	Built-in gate potential	V	1
RF	Gate-source effective forward-bias resistance	ohm	0
IS	Gate junction reverse saturation current (diode model)	A	1.70E-14
N	Gate junction ideality factor (diode model)	-	1.2
RDS	Additional output resistance for RF operation	ohm	400
CRF	Used with RDS to model frequency dependent output conductance	F	1.00E-08
RD	Drain ohmic resistance	ohm	1
RG	Gate resistance	ohm	0.5
RS	Source ohmic resistance	ohm	1
RIN	Channel resistance	ohm	2.07
CGSO	Zero bias gate-source junction capacitance (diode model)	F	2.60E-13
CGDO	Zero bias gate-drain junction capacitance (diode model)	F	9.00E-14
FC	Coefficient for forward bias depletion capacitance (diode model)	-	0.5
CDS	Drain-source capacitance	F	6.40E-14
CGS	Gate-source capacitance	F	0
CGD	Gate-drain capacitance	F	0
KF4	Flicker noise coefficient	-	0
AF	Flicker noise exponent	-	1
TNOM	Nominal ambient temperature at which these model parameters were derived	°C	27
XTI	Temperature exponent for saturation current		3
EG	Energy gap for temperature effect of IS	eV	1.11
VTOTC	VTO temperature coefficient	V/°C	0
BETATCE	Drain current exponential temperature coefficient	%°C	0
FFE	Flicker noise frequency exponent	-	1

7.2. ARCHIVO “.S2P”

```

! VDS=2V IDS=15MA
# GHZ S MA R 50
! SCATTERING PARAMETERS:
1 .983 -18.6 6.245 162.2 .019 78.9 .53 -13.5
2 .944 -37.5 5.964 144.3 .036 65.2 .507 -28.8
3 .896 -55.5 5.582 127.7 .050 53.6 .485 -42.6
4 .849 -72.6 5.327 112.4 .063 43.6 .464 -54.2
5 .797 -89.2 5.111 97.6 .074 33.1 .421 -65.4
6 .747 -103.7 4.799 83.4 .081 23.4 .370 -78.6
7 .691 -118.6 4.503 69.9 .085 13.9 .344 -90.7
8 .642 -132.8 4.277 57.0 .088 4.7 .303 -100.7
9 .600 -155.6 4.189 42.7 .093 -5.1 .271 -111.2
10 .567 -178.3 4.012 27.8 .096 -16.3 .228 -126.9
11 .534 170.3 3.846 15.5 .094 -26.5 .193 -145.5
12 .515 155.6 3.758 2.9 .093 -33.1 .177 -161.2
13 .555 128.7 3.569 -12.5 .091 -44.2 .137 176.3
14 .596 106.0 3.317 -27.1 .088 -55.6 .114 151.4
15 .592 91.3 3.214 -41.3 .087 -66.9 .141 123.9
16 .597 74.3 3.086 -56.8 .083 -81.1 .158 94.5
17 .619 59.2 2.756 -69.5 .071 -90.3 .134 68.1
18 .670 49.9 2.668 -79.4 .071 -97.3 .136 64.0
19 .668 33.0 2.623 -95.4 .069 -115.9 .169 51.0
20 .708 17.3 2.551 -111.1 .064 -131.4 .172 37.8
21 .757 8.2 2.447 -125.1 .061 -144.1 .159 18.7
22 .743 -2.5 2.325 -139.4 .063 -159.2 .135 14.7
23 .726 -21.1 2.224 -158.5 .065 179.4 .115 -1.3
24 .747 -39.6 2.063 -178.1 .067 158.8 .102 -39.6
25 .709 -52.6 2.024 167.9 .072 144.7 .136 -56.6
26 .683 -70.6 2.006 150.2 .083 132.8 .117 -71.3

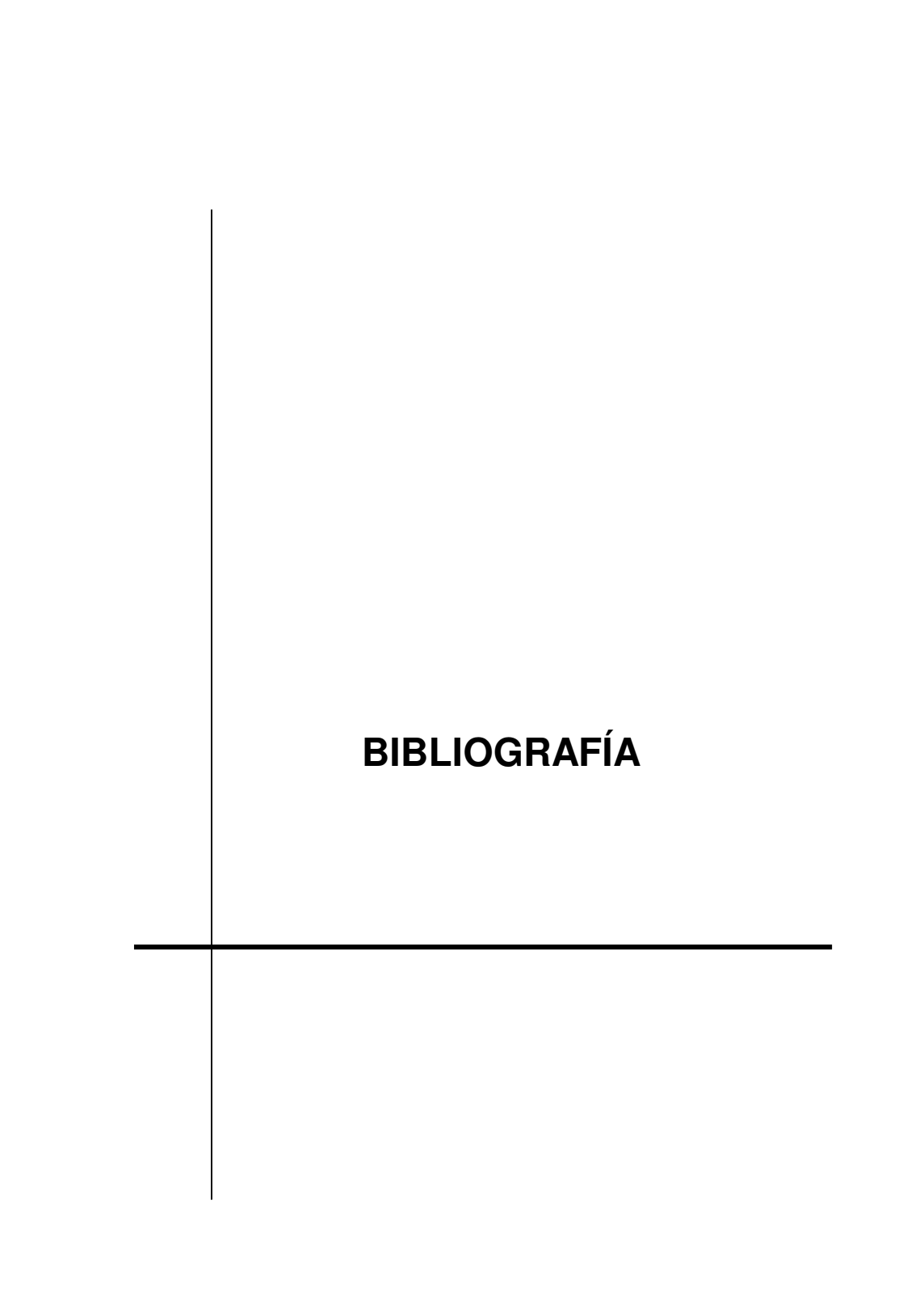
```

! NOISE PARAMETERS:

```

2 .37 .76 25 .26
4 .43 .65 56 .22
6 .48 .51 84 .16
8 .55 .41 118 .11
10 .61 .26 159 .08
12 .68 .26 -144 .08
14 .89 .32 -82 .18
16 1.1 .40 -46 .29
18 1.3 .40 -26 .45
20 1.45 .51 8 .55
22 1.69 .41 27 .61
24 1.83 .48 75 .59
26 2.05 .52 108 .40

```

BIBLIOGRAFÍA

BIBLIOGRAFÍA

[1] Dambrine, Gilles; Cappy, Alain; Heliodore, Frédéric; Playez, Edouard; “*A new method for determining the FET small-signal equivalent circuit*”, IEEE transactions on microwave theory and techniques, vol 36, nº 7, julio 1998.

[2] Berroth, Manfred y Bosch, Roland; “*Broad-band determination of the FET small-signal equivalent circuit*”, IEEE transactions on microwave theory and techniques, vol. 38, nº 7, julio 1990.

[3] Golio, J. Michael; “*Microwave MESFETs and HEMTs*”, Boston Artech House, 1991.

[4] Reina Tosina, Javier; Durán Díaz, Iván; Crespo Cárdenas, Carlos; “*Caracterización de circuitos para plataforma de comunicaciones móviles a 5 GHz*”, Actas XVIII Simposium Nacional URSI, Septiembre 2003.

[5] Manual ADS “*Non Linear Devices*”, Agilent Technologies, Mayo 2003.

[6] Manual ADS “*Circuit Simulation*”, Agilent Technologies, Mayo 2003.

[7] Manual ADS “*Introduction to Circuit Componentes*”, Agilent Technologies, Mayo 2003.

[8] Manual ADS *Tuning, Optimization and Statical Design*”, Agilent Technologies, Mayo 2003.

[9] Manual ADS “*Schematic Capture and Layout*”, Agilent Technologies, Mayo 2003.

[10] “*Capítulo IV: Diseño de amplificadores*”, apuntes asignatura de Microondas, Área de Teoría de la Señal del Departamento de Ingeniería Electrónica, Universidad de Sevilla.

[11] Manual ADS “*Amplifier Design Guide*”, Agilent Technologies, Mayo 2003.

[12] Manual ADS “*Expressions, Measurements and Simulation Data Processing*”, Agilent Technologies, Mayo 2003.

[13] “*N9000, PTFE laminates and bolding films*”, Parnelko.

[14] Manual ADS “*LineCalc*”, Agilent Technologies, Mayo 2003.

[15] “*Tema 3: Subsistemas de radio*”, apuntes asignatura de Radiación y Radiocomunicación, Área de Teoría de la Señal del Departamento de Ingeniería Electrónica, Universidad de Sevilla.

[16] Howard, Andy; *“Load-Pull Simulation using ADS”*, presentación de PowerPoint, 28 de mayo del 2002, Agilent Technologies.

[17] Manual ADS *“User-Defined Models: Custom Modelling with Symbolically-Defined Devices”*, Agilent Technologies, Mayo 2003.

[18] Vendelin, George G.; Pavio, Anthony M.; Rohde, Ulrich L.; *“Microwave Circuit Design, using linear and nonlinear techniques”*, Wiley-Interscience, 1990.

[19] Maas, Stephen A.; *“Nonlinear Microwave Circuits”*, Norwood Artech House, 1988.

[20] Manual ADS *“Quick Start: Simulation controllers”*, Agilent Technologies, Mayo 2003.

[21] Anaya de Vega, Enrique; PFC *“Programa APLAC: Análisis de circuitos de microondas”*, Sevilla, Julio 2003.

[22] Galán Martín, Rubén Darío; PFC *“Programa de simulación APLAC: análisis de circuitos no lineales”*, Sevilla, Julio 2003.

[23] Stapleton, Shawn; *“Adaptative digital Predistorsion of power amplifiers”*, Agilent Technologies, Noviembre 2000.

[24] *“Capítulo II: Análisis de Redes de Microondas”*, apuntes asignatura de Microondas, Área de Teoría de la Señal del Departamento de Ingeniería Electrónica, Universidad de Sevilla.

[25] González, G.; *“Design of Amplifiers and Oscillators by the S-parameter Method”*, Prentice Hall, 1984.